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**Confirmation Letter** 

To,

Linda Varghese

Published in : Volume 3 | Issue 10 | 2016-10-13



Subject: Publication of paper at International Journal of Emerging Technologies and Innovative Research.

Dear Author,

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Published URL: http://www.jetir.org/view?paper=JETIR1610034 : Linda Varghese, Neeraj M.G, Mevin Varghese Authors

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